

## ABSTRACT OF THE DISCLOSURE

According to the present invention, there is provided an insulator capacitance analyzer for analyzing  
5 C-V characteristics of a first MIS structure having unknown capacitance, which includes: a capacitance structure having known capacitance and configured so as to be serially connectable to the first MIS structure; and a measuring section for measuring synthesis  
10 capacitance of the serially-connected first MIS structure and capacitance structure.

10003258 120601